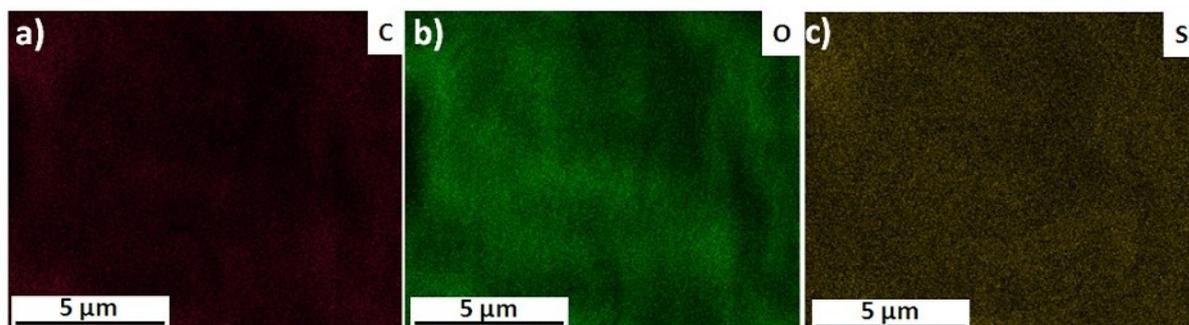


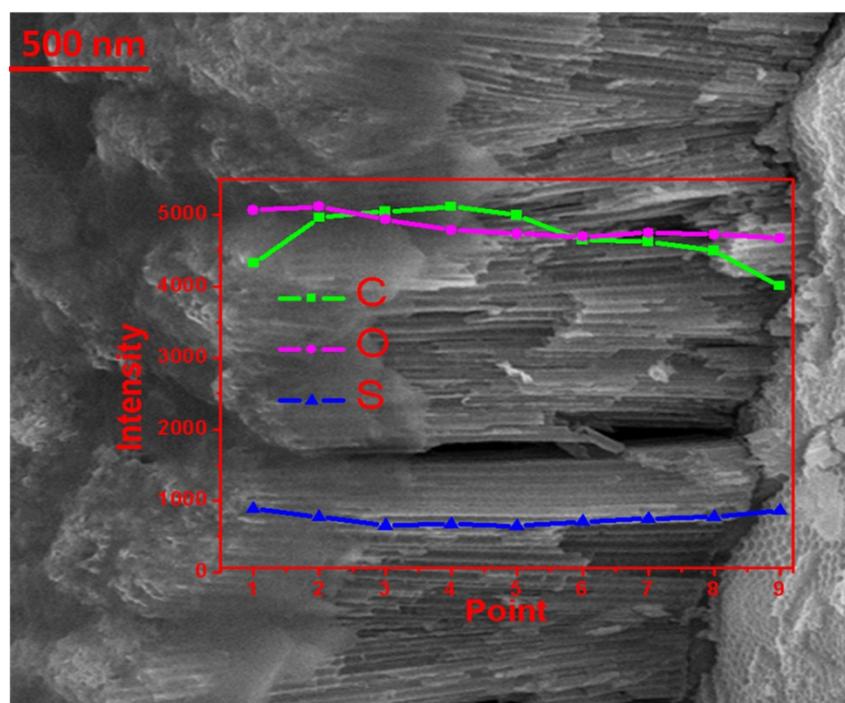
## Electronic supplementary information

### *Highly stable organic-inorganic junction composed of hydrogenated titania nanotubes infiltrated by conducting polymer*

#### EDX analysis performed at the surface and across the titania layer



**Fig. S1** Distribution of (a) carbon, (b) oxygen and (c) sulphur over the H-TiO<sub>2</sub>NTs/pEDOT:PSS composite layer.



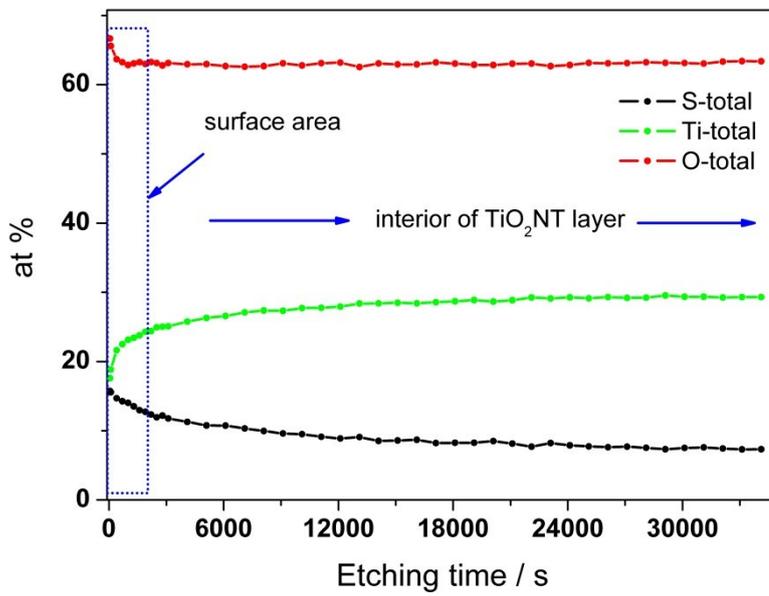
**Fig. S2** The distribution of carbon, oxygen and sulphur across the composite H-TiO<sub>2</sub>NTs/pEDOT:PSS material.

### Photography of samples



**Fig. S3** Photography of a) H-TiO<sub>2</sub>NTs and b) H-TiO<sub>2</sub>NTs/pEDOT:PSS sample.

### XPS analysis



**Fig. S4** A distribution of sulphur, carbon and oxygen across the H-TiO<sub>2</sub>NTs/pEDOT:PSS samples inspected under the XPS etching mode.

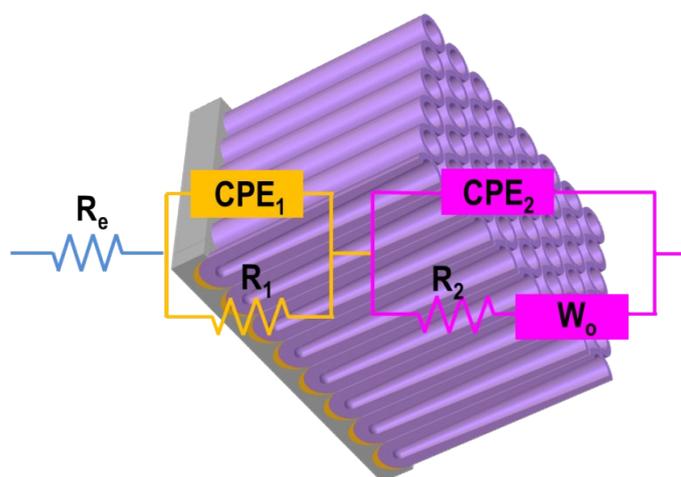
## Electrochemical Impedance spectroscopy

### The interpretation of EEQC elements

The electrolyte resistance was assigned as  $R_e$ , whereas the subsequent EEQC parts were attributed to the compact oxide film ( $CPE_1R_1$ ) and highly ordered nanotubes ( $CPE_2R_2W_o$ ). As it was reported by Brug<sup>1</sup>, a constant phase element was used because of electrode inhomogeneity. The impedance of  $CPE$  is defined as  $Z = Q^{-1}(i\omega)^{-\alpha}$ , where energy dispersion denoted as  $\alpha$  is considered. Its value was in the range between 0.85 and 0.99. In the EEQC part attributed to processes occurring in the tubular film, the Warburg open element is present. The  $W_o$  is assigned to the finite length diffusion with reflective boundary and described by:

$$Z_{W_o}(\omega) = \frac{\omega_{or}}{\sqrt{\omega}}(1-j)\coth[W_{oc}\sqrt{j\omega}] \quad (3)$$

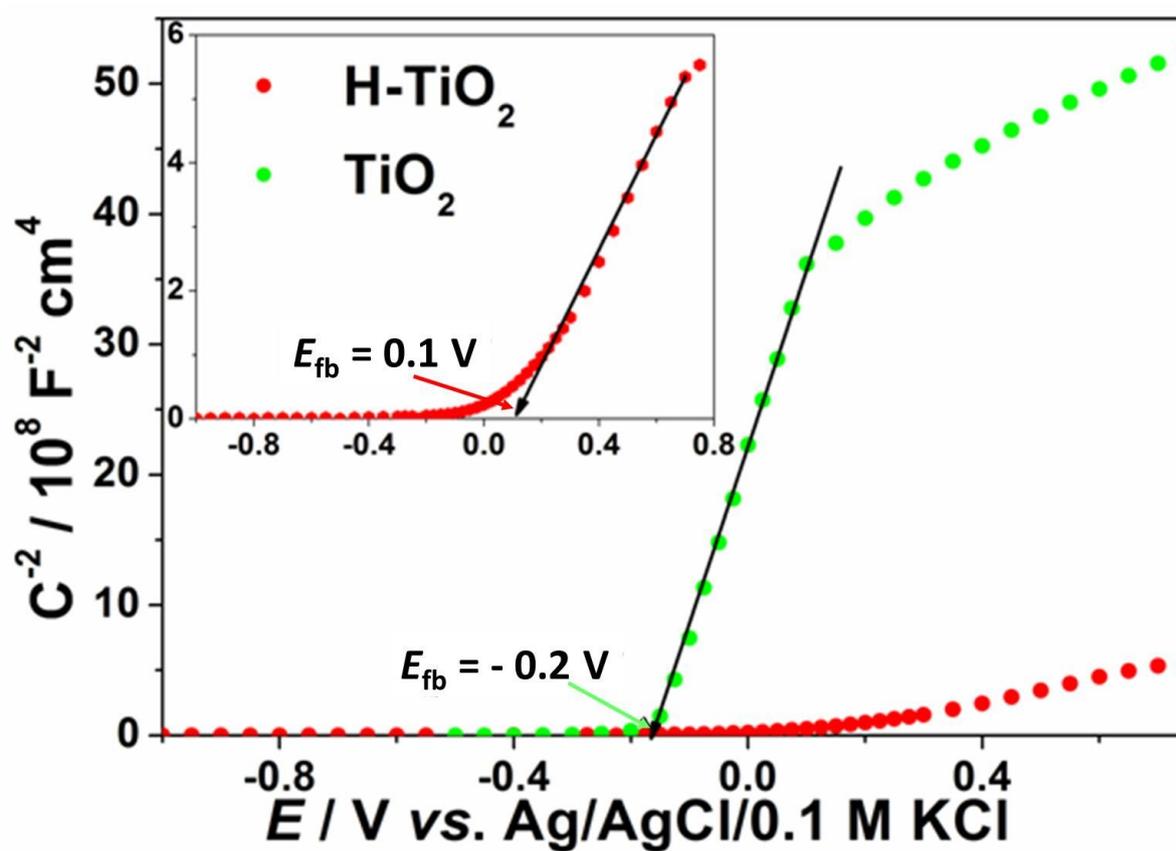
where  $W_{or}$  stays for Warburg coefficient,  $W_{oc} = d/D^{0.5}$ . In the case of the studied material,  $W_o$  is related to the charge transport within tubular titania down to the blocking metal oxide support. The calculated values for each element in EEQC for a pristine and hydrogenated sample are collected in Table S1. As it could be seen, in the case of pure  $TiO_2$ , the huge difference between  $R_1$  and  $R_2$  is present due to high conductivity of the walls when compared to the base semiconductor film.<sup>2</sup> Thus, the observed response is mainly attributed to the bottom oxide, while the  $TiO_2$  nanotubular layer has an impact on the shift of the Fermi level of the material and surface chemistry effects.



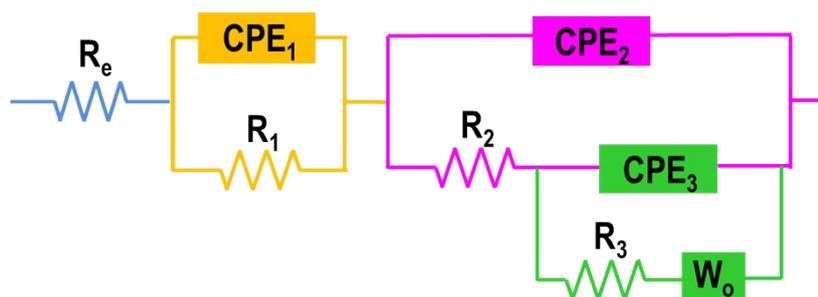
**Fig. S5** The scheme of an electric equivalent circuit used for impedance spectra fitting for pure and hydrogenated titania samples.

**Table S1.** The calculated values for electric equivalent circuit elements for pure and hydrogenated TiO<sub>2</sub> titania nanotubes.

material	$R_e / \Omega$	$R_1 / \Omega$	$CPE_1 / \Omega^{-1}s^n$	$R_2 / \Omega$	$CPE_2 / \Omega^{-1}s^n$	$W_{or} / \Omega s^{-0.5}$	$W_{oc}$
TiO <sub>2</sub>	5.2	7756	$1 \times 10^{-5}$	7.14	$7.5 \times 10^{-6}$	5.24	$1.98 \times 10^{-5}$
H-TiO <sub>2</sub>	8.1	0.64	$8.37 \times 10^{-5}$	4.46	$1.8 \times 10^{-4}$	$9.2 \times 10^{-6}$	$8.78 \times 10^{-10}$



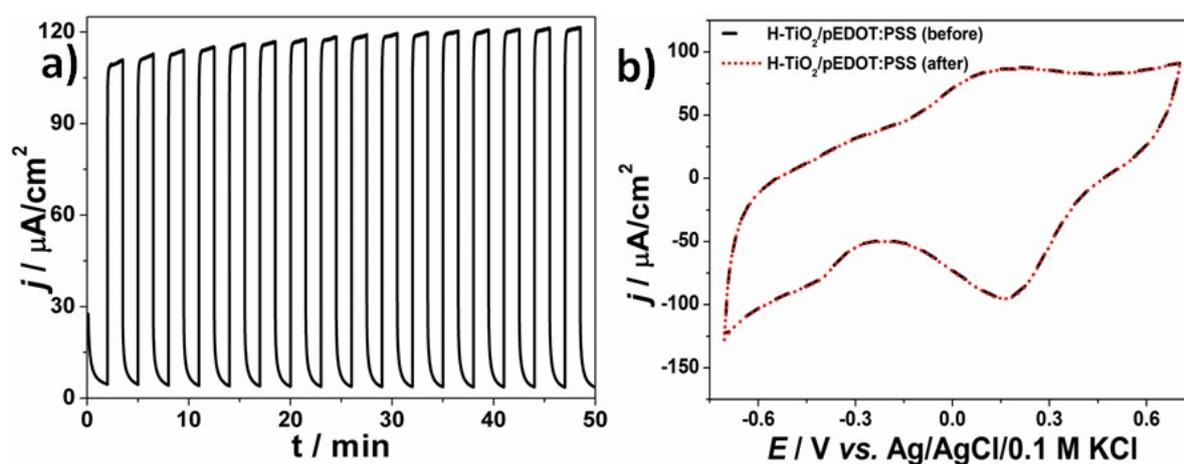
**Fig. S6** The Mott-Schottky plot for pristine and hydrogenated TiO<sub>2</sub>NTs.



**Fig. S7** The scheme of the electric equivalent circuit used for impedance spectra fitting for composite H-TiO<sub>2</sub>NTs/pEDOT:PSS material.

**Table S2** The calculated values for electric equivalent circuit elements for H-TiO<sub>2</sub>NTs/pEDOT:PSS ( $s = 0.5 \text{ cm}^2$ ).

element	value	element	value
$R_e / \Omega$	7.2	$CPE_3 / \Omega^{-1}s^n$	$2 \times 10^{-5}$
$CPE_1 / \Omega^{-1}s^n$	$5.05 \times 10^{-4}$	$R_3 / \Omega$	197.29
$R_1 / \Omega$	10.12	$W_{or} / \Omega s^{-0.5}$	$9.33 \times 10^{-4}$
$CPE_2 / \Omega^{-1}s^n$	$1.73 \times 10^{-4}$	$W_{oc} / s^{-0.5}$	$2.77 \times 10^{-7}$
$R_2 / \Omega$	742.96		



**Fig. S8** a) Transient photocurrent registered for H-TiO<sub>2</sub>NTs/pEDOT:PSS under prolonged irradiation, b) cyclic voltammety curve of composite electrode obtained before and after photocurrent measurements.

## References:

- 1 G. J. Brug, A. L. G. Van Den Eeden, M. Sluyters-Rehbach and J. H. Sluyters, *J Electroanal. Chem.*, 1984, **175**, 275.
- 2 H. Wu, D. Li, X. Zhu, C. Yang, D. Liu, X. Chen, Y. Song and L. Lu, *Electrochim. Acta*, 2014, **116**, 129.